

TR Profile + DH-8





TR Profile + DH-8

INTRODUCTION

The TR Profile and TR Profile DH-8 are extremely precise surface roughness measuring instruments, built for the use in the workshop and on production lines as well as in the lab.

From the simple roughness measurement without accessories, directly on the machine, to the measurements in the laboratory with measuring support, special tracers and other accessories, including the recording of contours, the TR Profile and TR Profile DH-8 offer maximum flexibility for surface analysis.

The tracers are the core pieces of the roughness meters. They are, to a wide extent, the determining factor of the precision of the measuring values obtained. The great choice of tracers is the result of decades of experience in the construction of such probes. The traversing unit with an integrated reference flat allows to effect precise measurements also with skidless tracers (VHF versions). The traversing units of TR Profile and TR Profile DH-8 are identical.

All instruments can be connected to a PC. They are delivered with a simple analysis software.

LINEARITY AND MEASURING ACCURACY

APPLICATION FLEXIBILITY

LARGE RANGE OF ACCESSORIES

REMOVABLE TRAVERSING UNITS

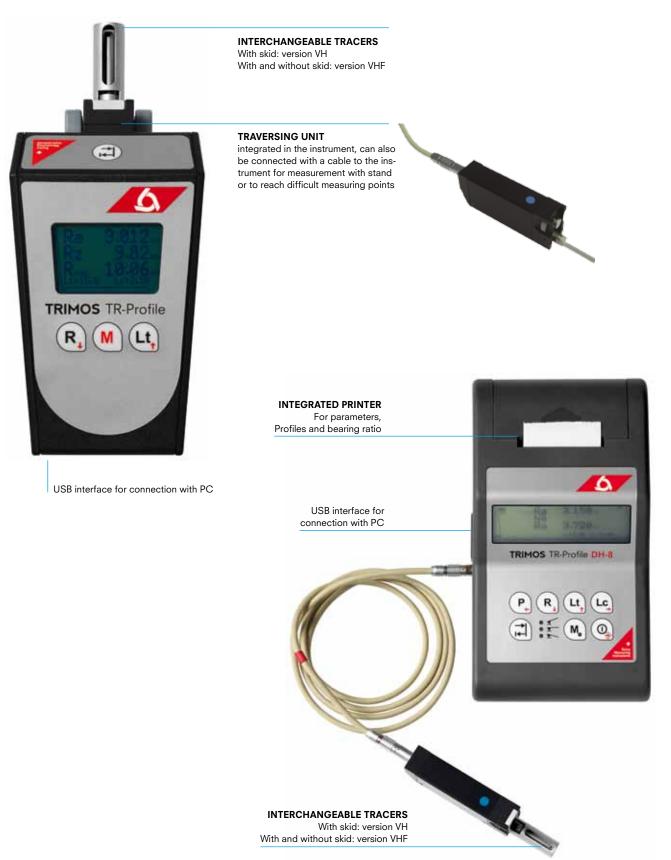
RECHARGEABLE BATTERY FOR MOBILE APPLICATIONS

TRACERS WITH AND WITHOUT SKID

EASE OF USE



DESCRIPTION



TR Profile + DH-8

DISPLAY/SOFTWARE

TR PROFILE

Extremely simple and intuitive use. Only 4 buttons to access to all functions.

Parameters:

ISO/DIN: Ra, Rz (DIN), Rmax, R3z, Rt, Rq (RMS), Rk, Rp, Rv, Rpk, Rvk, MR1, MR2, Rpc, C1, C2, bearing ratio Rmr, C0, Cz JIS: Ra (JIS), Rz (JIS) ISO 12085: R, AR, Rx

DISPLAY OF PARAMETERS AND PROFILES

MEMORY FOR 15 MEASURING PROFILES

AUTOMATIC CALIBRATION

CUT-OFF FIRMLY ASSIGNED TO THE TRAVERSING LENGTH

USB DATA OUTPUT

MENUS IN 6 DIFFERENT LANGUAGES

TR PROFILE DH-8

Multifunctional and polyvalent measuring instrument for roughness and contour measurement.

Parameters:

ISO/DIN: Ra, Rz (DIN), Rmax, R3z, Rt, Rq (RMS), Rk, Rp, Rv, Rpk, Rvk, MR1, MR2, Rpc, C1, C2, bearing ratio Rmr, C0, Cz JIS: Ra (JIS), Rz (JIS) ISO 12085: R, AR, Rx

DISPLAY OF PARAMETERS AND PROFILES

MEMORY FOR 50 MEASURING PROFILES

AUTOMATIC CALIBRATION

5 MEASURING LENGTHS, ALL SELECTABLE BETWEEN 0.5 AND 15.0 MM

MEASURING SPEED SELECTABLE

CALIBRATION FOR MAX. 8 TRACERS

8 MEASURING PROGRAMS

TOLERANCE INDICATION

KEY LOCK FOR LT, LC AND R TO PREVENT ANY SETTINGS MISTAKES

USB OUTPUT FOR DATA TRANSFER (OPTION: BLUETOOTH)

CONTOUR MEASUREMENTS

MENUS IN 6 DIFFERENT LANGUAGES







DISPLAY/SOFTWARE

SOFTWARE DIASOFT

DIASOFT is a multilingual software that gives the opportunity to further improve the DIAVITE possibilities. This software will work out an even greater number of roughness parameters and will be a help for the memorization and the presention of your measurements protocols. All measured values can be analysed and compared. The software most adapted to your needs will doubtlessly be found among the 4 existing versions :

Basic (TA-SW-601, included in standard delivery)

Basic software with Ra, Rq, Rv, Rp, Rt, Sm, Rsk, Rku, Rz, RTp, RHTp, RDq, RPc, roughness curve, Abbott curve. Predefined protocol.

• Standard (TA-SW-602)

Same as «Basic», additionally with RLq, Rlo, RzJIS, R3z, waviness and roughness profile on the same curve, zoom functions, symmetry, comparison of profiles etc. Protocols can be customized individually.

• Automotive (TA-SW-603)

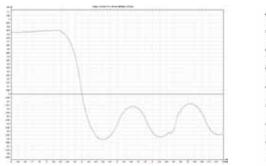
Same as «Standard», additionally with ISO 12085 (CNO-MO), ISO 13565, (parameter Rk)

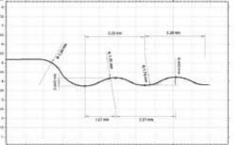
• Expert (TA-SW-604)

Same as «Automotive», additionally with analysis of series of profiles and a lot more features for surface analysis. The most complete offer for the specialist, now and in the future.

MEASUREMENT OF CONTOURS

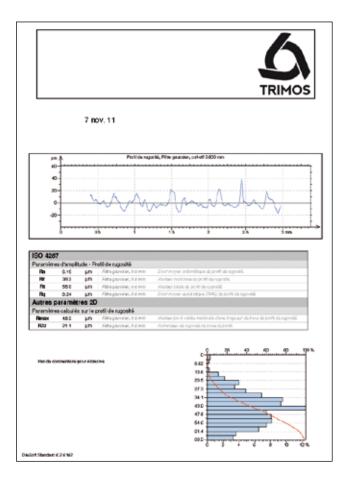
The TR Profile DH-8/VHF now offers the possibility, as an option, to precisely measure contours. For this purpose, a special contour measuring tracer is needed, in combination with a specific software module.





The softwares DIASOFT Standard, Automotive and Expert can be equipped with the following modules:

- Contour module Simple (TA-SW-610)
- Contour module Advanced (TA-SW-611)



TR Profile + DH-8

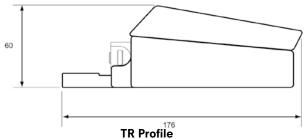
TECHNICAL SPECIFICATIONS

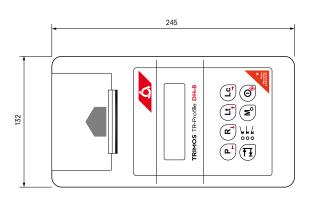
		TR Profile	TR Profile DH-8		
Measuring range (Ra, Rq)	μm	20			
Measuring range (other parameters)	μm	350			
Measuring range of tracers	μm	350			
Max. permissible errors Ra	%	5%	, D		
Repeatability (Ra, 1o)	μm	0.00)9		
Resolution (Ra, Rq)	μm	0.01 (<0.1 µ	ım: 0.001)		
Resolution (other parameters)	μm	0.1			
Vertical resolution of tracers	μm	0.01			
Horizontal resolution of tracers	μm	1			
Measuring speed	mm/s	0.5 0.25/0.5/1.0			
Measuring force, tracers with skid	Ν	< 0.15			
Measuring force, tracers without skid	mN	< 0.	5		
Diamond tip radius	μm	5 μm, 90° (standard) or 2 μm, 60° (option)			
Cutoffs Ic	mm	0.08/0.25/0.8/2.5			
Measuring lengths It	mm	0.48/1.50/4.8/15.0 0.5 ÷ 15 (programmable			
Relative humidity	%	20 ÷ 80			

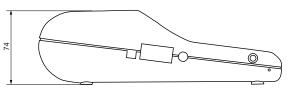
Contour Tracer (TA-MS-650)		
Horizontal measuring range (X)	mm	15
Vertical measuring range (Z)	mm	4
Max. permissible errors (Z)	μm	5
Tracing angle: rising flanks	٥	< 77
Tracing angle: falling flanks	٥	< 88

DIAGRAM











STANDARD INSTRUMENT

Instrument according to specifications
Traversing unit VH or VHF
Standard tracer (TA-MS-601)
Adapter with connecting cable (TA-EL-601)
Roughness standard, Ra=3.0 µm (TA-MG-609)
Charging unit
USB cable
Screw driver
User's manual (750 50 0040 03) and quick guide (750 50 0036 03)
Certificate of quality
Software DIASOFT Basic (TA-SW-601)
Carrying case
The TR Profile DH-8 instruments are supplied as follows:
Instrument according to specifications

Instrument according to specifications
Traversing unit VH or VHF
Standard tracer (TA-MS-601)
Roughness standard, Ra=3.0 µm (TA-MG-609)
Charging unit
USB cable
Screw driver
User's manual (750 50 0042 00) and quick guide (750 50 0043 03)
Certificate of quality
Software DIASOFT Basic (TA-SW-601)
Carrying case

CODE NUMBER

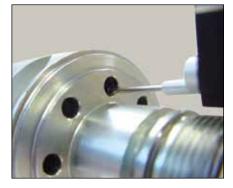
TR Profile	TR Profile DH-8	
TR Profile VH 700 401 10 01	TR Profile DH-8/VH 700 401 10 51	For tracers with skid
TR Profile VHF 700 401 10 02	TR Profile DH-8/VHF 700 401 10 52	For tracers with and without skid
	TR Profile DH-8/VHF-CP-S 700 401 10 61	Set for contour measurements Simple - TR Profile DH-8/VHF - Contour tracer (TA-MS-650) - Contour standard (TA-MG-651) - Software DIASOFT Standard (TA-SW-602) - Contour module Simple (TA-SW-610)
	TR Profile DH-8/VHF-CP-A 700 401 10 62	Set for contour measurements Advanced - TR Profile DH-8/VHF - Contour tracer (TA-MS-650) - Contour standard (TA-MG-651) - Software DIASOFT Standard (TA-SW-602) - Contour module Advanced (TA-SW-611)

TR Profile + DH-8

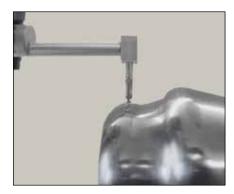
APPLICATIONS



Checking of surface roughness near a shoulder (TA-MS-601)



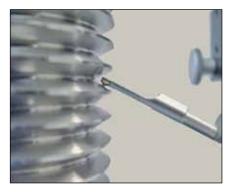
Measurement in small bores (TA-MS-605)



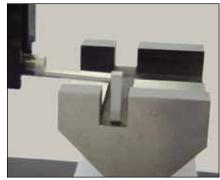
Measuring surface roughness of a polished part (TA-MS-607)



Checking at recessed measuring points (TA-MS-609)



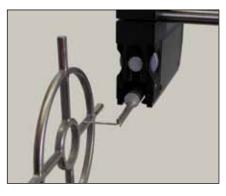
Checking of thread profile roughness of a thread plug gage (TA-MS-620)



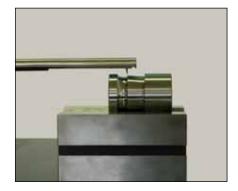
Checking in a recess using an appropriate probe (TA-MS-608)



Radial roughness measurement (TA-MS-621)



Transversal flank measurement (TA-MS-627)



Contour measurement with TR Profile DH-8/VHF (TA-MS-650)





INTRODUCTION

The TR Scan offers an innovative alternative to classical surface measurement. Its modular concept, allowing adaptation to each application, and its simple use, make it very efficient in the workshop. Because of its simplicity of use, the TR Scan can be operated by workshop personnel to get reliable results secured with minimum training. All measured surfaces can be treated according to current international standards such as ISO, DIN, JIS, ASME, CNOMO etc., as well as the upcoming ISO 25178 3D standard.

The TR Scan is completely designed and manufactured in Switzerland according to the highest quality standards. Robustness, reliability and longevity are part of our tradition. Trimos instruments have been used in workshops and labs for over 30 years.

The interchangeability of the measuring heads gives the possibility to select the most appropriate technology for each application. This flexibility allows the characterization of surfaces in numerous application fields, such as mechanical industry (all types of machined surfaces), car and aerospace industries, photovoltaics, as well as plastics, papers, imprints, fibrous materials, wood, abrasives, paint, cosmetics, etc.

MEASURING RESULTS FULLY COMPARABLE TO CLASSICAL SYSTEMS

COMPLIES TO ALL INTERNATIONAL STANDARDS

INTUITIVE, EASY TO USE INTERFACE

ROBUST INDUSTRIAL SYSTEM FOR THE WORKSHOP

POSSIBLE AUTOMATED MEASUREMENTS

MODULAR AND COMPACT CONCEPT

MEASUREMENT AND ANALYSIS WITHIN SECONDS



DESCRIPTION



Motorized table (XY)

DISPLAY/SOFTWARE

TRIMOS NANOWARE MEASURE

This exclusive software allows the handling of the instrument (positioning and configuration of all measurements).

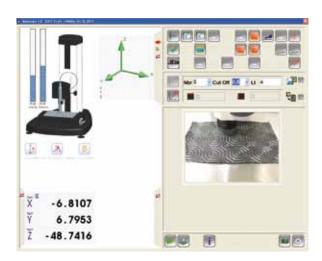
Positioning in X,Y,Z is performed either automatically by predefined parameters or via the use of an intuitive joystick aided by a integrated positioning laser and a camera (optional).

Once positioned, measurements are taken automatically with one click or via the use of a manual size parameter in a few seconds.

INTUITIVE POSITIONING

INSTANT MEASUREMENT

PROGRAMMABLE MEASUREMENTS WITH PICTURE



TRIMOS NANOWARE ANALYSIS

This software allows the analysis of all measured surfaces according to current international standards such as ISO, DIN, JIS, ASME, CNOMO etc., as well as the 3D standard ISO 25178.

Analysis can be performed automatically by the use of a template, or the user can have direct access to the raw data. The incorporated analysis software is powered by Mountains®, the most powerful and recognized 2D/3D surface analysis software available.

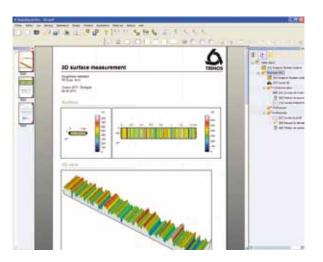
Reports are automatically generated during analysis. Any report can be used as a template later.

POWERFUL ANALYSIS

PROFESSIONAL REPORTING

SUITABLE MODULE FOR EACH APPLICATION NEED

COMPLIES TO ALL INTERNATIONAL STANDARDS



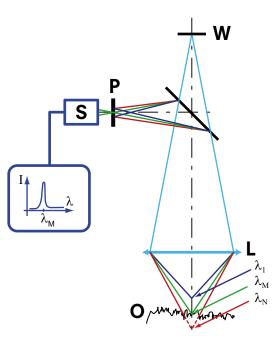




THE CCM TECHNOLOGY

Chromatic Confocal Microscopy (CCM) has been acknowledged worldwide as an accurate and reliable technique for non-contact surface measurement. A chromatic lens L generates the image of a point white-light source W as a continuum of monochromatic images located on the optical axis ("Chromatic coding"). A sample O is located inside the color-coded segment and its surface scatters the incident light beam. The backscattered light passes through the chromatic lens L in the opposite direction, and arrives at a pinhole P which filters out all wavelengths except a single wavelength, λM . The collected light is analysed by a spectrometer S. The sample position is directly related to the detected wavelength.

- High resolution
- Works on all types of sample materials
- Wide choice of measuring ranges
- Steep slope compatibility
- Coaxial (no shadowing)
- Recognised method by ISO 25178



CCM P1 MEASURING HEAD







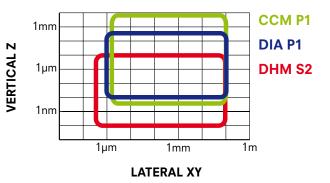
CCM-P1 (support & spectrometer)

TA-MI-701 ÷ 713 Optical pen

COMPLEMENTARY TECHNOLOGIES

There is no universal technology for surface measurement. The modularity of the TR Scan allows the use of the best adapted head for each application.

The diagram here below shows the application field of the TR Scan and of its various measuring heads according to the material structure.



MEASURING HEADS

DHM S1 & S2

- DHM Technology:
- Smooth, grinded and polished surfaces
- Steel, aluminium, titanium, silicon, gold, ceramics, glass
- High precision and speed, 2D/3D

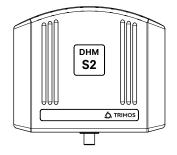
CCM P1

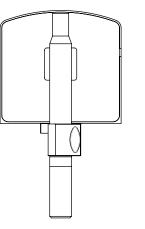
- Chromatic Confocal Technology:
- Machined and rough surfaces, micro-structures
- Metals, plastics, abrasives, papers, textiles, cosmetics
- Large vertical range, all materials, 2D/3D

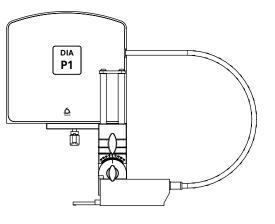
DIA P1

Diamond Stylus Tip Technology:

- Roughness measurement with contact
- Classical roughness measurements (2D)
- Internal measurements







TECHNICAL SPECIFICATIONS

TR Scan		101	201	301
Horizontal measuring range X	mm	-	100	100
Horizontal measuring range Y	mm	100		100
Vertical measuring range Z	mm		240	
Measuring system resolution XYZ	μm	0.1		
Positioning accuracy XYZ	μm	1		
Rectitude of the guideways XY	μm	1.5		
Max weight of the part	kg	20		

Measuring heads		DHM S1	DHM S2	CCM P1	DIA P1
Vertical resolution (Z)	nm	1	1	8 ÷ 22 ²⁾	10
Lateral resolution (XY)	μm	0.6	0.6	$0.9 \div 3.5^{2}$	1
Typical measuring range Ra ¹⁾	μm	0.4	1.6	>200 2)	20
Vertical measuring range ¹⁾	μm	3	7	$130 \div 400^{2}$	350
Max. permissible errors Ra	%	1%	1%	$1\% \div 5\% ^{2)}$	5%
Repeatability (Ra, 1o)	nm	< 0.1	< 0.1	$<5 \div 20^{2}$	9
Sample reflectivity	%	< 1% ÷ 100%	< 1% ÷ 100%	1% ÷ 100%	-
Field of view	mm	0.25 x 0.25	0.25 X 0.25	-	-

¹⁾ Values may differ depending on the surface texture

2) Objective dependent



DIAGRAM

STANDARD INSTRUMENT

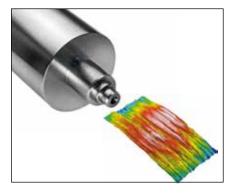
The TR Scan instruments are supplied as follows:
Instrument according to specification (without measuring head)
1 measuring head (DHM S1, DHM S2, CCM P1+TA-MI-701/TA-MI-708)
PC with 1 TFT screen
Nanoware Measure and Nanoware Analysis software (according to selected model)
User's manual (750 50 0028 03)

CODE NUMBER

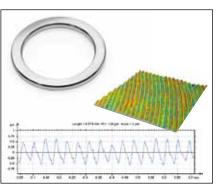
TR Scan	Purpose	Meas. head	Axes	Software
TRS201CCM 700 405 20 11	Non-contact profiles measurements 2D	CCM P1	- 1 vertical axis Z - 1 horizontal axis X	Nanoware LT (2D analysis)
TRS201DHM 700 405 20 21	Extended profiles measurements 3D, metallic parts	DHM S2	- 1 vertical axis Z - 1 horizontal axis X	Nanoware STT (2D/3D analysis)
TRS301DHM 700 405 30 11	3D measurements, metallic parts	DHM S2	- 1 vertical axis Z - 2 horizontal axes XY	Nanoware STT (2D/3D analysis)

The TR Scan can also be specifically equipped according to the needs for each application (head(s) and measuring table, software). An exhaustive list of equipments can be found in the accessories section.

APPLICATIONS



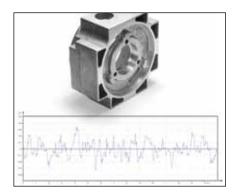
Surface spinning measurement on a steel printing roll (DHM S2)



Verification of an aluminium ring joint gasket for the aircraft industry (DHM S2)



Texture analysis of a chemically polished titanium surface (DHM S2)



Classical 2D internal roughness measurement (DIA P1)



TR SCAN PREMIUM



TR SCAN PREMIUM

INTRODUCTION

TR Scan Premium allows the measuring of the most sensitive surfaces with astounding speed and precision. It has become unavoidable in many cases for hi-tech applications, when the traditional measuring by contact has reached its limits. Medical appliances, prosthesis, wafers, MEMS, semiconductors, metallic layers deposits, polymer films, optical components, research and development, quality control, are the areas of expertise of TR Scan Premium.

The heart of the system, Trimos DHM[®] (Digital Holographic Microscopy), constitutes a derivation of a technology used in the biomedical engineering field. The system itself is based on the physical characteristics of the hologram for the topography generation of the analysed surface. This technology for checking industrial surfaces is exclusively used by Trimos. Its most distinctive feature to competitive products is the possibility of measuring extreme reflecting, mirror-polished or very small surfaces.

The exceptional high measuring speed coupled with an accuracy range of a nanometre form the main advantages of the TR Scan. Only some microseconds are needed for the acquisition of a three dimensional image (x, y, z) with a million points. This exceptional acquisition speed allows ignoring all problems traceable to vibrations, the traditional enemy of the majority of optical measuring systems. The mentioned advantages prove an enhanced productivity and a limited investment.

EXCEPTIONAL FAST MEASURING SPEED

INSENSITIVE TO VIBRATION

VERTICAL RESOLUTION IN NANOMETER RANGE

EXTREME SIMPLE POSITIONING OF THE PART THANKS TO LASER ALIGNMENT (DHM)

NON-CONTACT MEASURING, NON DESTRUCTIVE

SOFTWARE AT THE TOP OF THE TECHNOLOGY

PRE-PROGRAMMED MEASURING PROCESSES

COMPATIBLE WITH 2D AND 3D STANDARDS



DESCRIPTION



TR SCAN PREMIUM

DISPLAY/SOFTWARE

TRIMOS NANOWARE MEASURE

This exclusive software allows the handling of the instrument (positioning and configuration of all measurements).

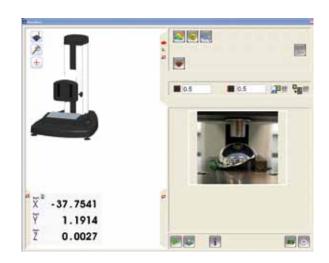
Positioning in X,Y,Z is performed either automatically by predefined parameters or via the use of an intuitive joystick aided by a integrated positioning laser and a camera (optional).

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Analysis can be performed automatically by the use of a template or the user can have direct access to the raw data. The incorporated analysis software is powered by Mountains®, the most powerful and recognized 2D/3D surface analysis software available.

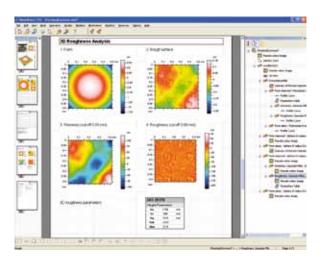
Reports are automatically generated during analysis. Any report can be used as a template later.

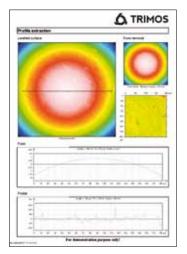
POWERFUL ANALYSIS

PROFESSIONAL REPORTING

SUITABLE MODULE FOR EACH APPLICATION NEED

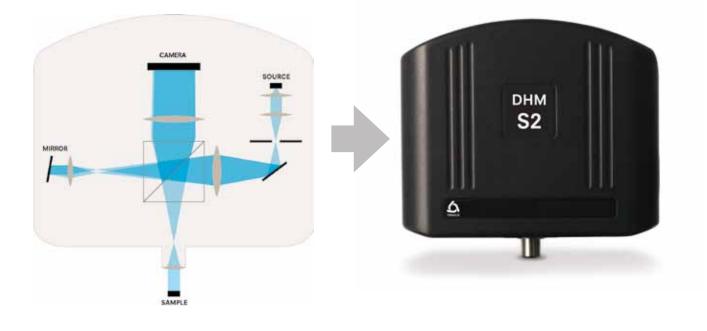
COMPLIES TO ALL INTERNATIONAL STANDARDS







THE DHM TECHNOLOGY



DHM® (Digital Holographic Microscopy) is a non-contact surface measurement technology originally developed for the biotech and medical industry. DHM generates a high-resolution 3D digital image of a sample using the principle of holography. A hologram generated by combining a coherent reference wave with the wave received from a sample is recorded by a CCD camera and transmitted to a computer for numerical reconstruction.

A single hologram is acquired in a few microseconds, making the whole system insensitive to vibrations. Software procedures allows computation of the complete wavefront emanating from an object and provides:

 Intensity images providing the same contrast as with classical optical microscopy • Phase images providing quanti tative data, defined at a sub-wavelength scale, used for accurate and stable 3D measurements.

The phase image reveals the surface topography with a sub-nanometric vertical resolution. This digital approach to holography allows the application of computer-based procedures at a level never reached in optical microscopy so far. In particular the DHM principle features software compensation of optical aberrations, digital image focusing and numerical compensation for sample tilt and environmental disturbances, making DHM instruments robust and easy to use for routine inspections at the nanometer and micrometer scale.DHM is used exclusively by Trimos for surface texture measurement. This technology has numerous advantages compared to other contact and non-contact measurement technologies: in particular extremely fast measurements, high resolution, simple working process no moving parts and no requirement for special environmental conditions.

- Acquisition in a few microseconds
- Vibration incensitive
- High image quality
- Subnanometric resolution
- No moving parts
- No requirement for special environmental conditions

DHM is a recognized surface texture measurement method according to the standard ISO 25178-6

TR SCAN PREMIUM

MEASURING HEADS

DHM S1 & S2

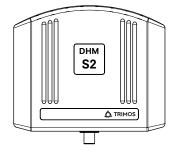
- DHM Technology:
- Smooth, grinded and polished surfaces
- Steel, aluminum, titanium, silicon, gold, ceramics, glass
- High precision and speed, 2D/3D

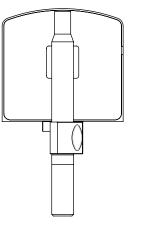
CCM P1

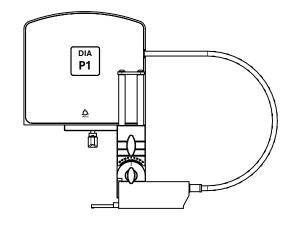
- Chromatic Confocal Technology:
- Machined and rough surfaces, micro-structures
- Metals, plastics, abrasives, papers, textiles, cosmetics
- Large vertical range, all materials, 2D/3D

DIA P1

- Diamond Stylus Tip Technology:
- Roughness measurement with contact
- Classical roughness measurements (2D)
- Internal measurements







TECHNICAL SPECIFICATIONS

TR Scan Premium		101	301
Horizontal measuring range X	mm	-	100
Horizontal measuring range Y	mm	-	100
Vertical measuring range Z	mm	2	40
Measuring system resolution XYZ	μm	0.1	
Positioning accuracy XYZ	μm	1	
Rectitude of the guideways XY	μm	0	.3
Max weight of the part	kg		20

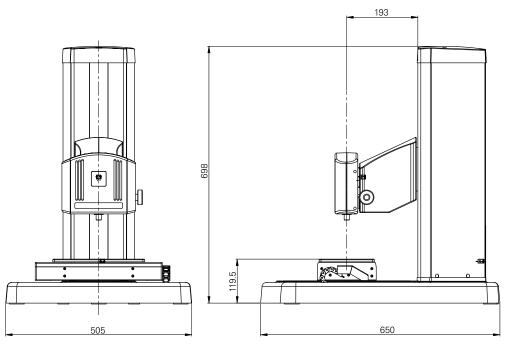
Measuring Heads		DHM S1	DHM S2	CCM P1	DIA P1
Vertical resolution (Z)	nm	0.1	0.1	8 ÷ 780 ²⁾	10
Lateral resolution (XY)	μm	0.6	0.6	$0.9 \div 14^{2)}$	1
Typical measuring range Ra ¹⁾	μm	0.4	1.6	$0.012 \div > 200^{2}$	20
Vertical measuring range ¹⁾	μm	3	7	$130 \div 24000^{2}$	350
Max. permissible errors Ra	%	1%	1%	$1\% \div 5\% ^{2)}$	5%
Repeatability (Ra, 1)	nm	< 0.1	< 0.1	$<5 \div 25^{2}$	9
Sample reflectivity	%	< 1% ÷ 100%	< 1% ÷ 100%	1% ÷ 100%	-
Field of view	mm	0.25 x 0.25	0.25 X 0.25	-	-

¹⁾ Values may differ depending on the surface texture

2) Objective dependent



DIAGRAM



STANDARD INSTRUMENT

The TR Scan Premium instruments are supplied as follows:
Instrument according to specification (without measuring head)
1 measuring head (DHM S1, DHM S2, CCM P1+TA-MI-701 ÷ 713)
PC with 1 TFT screen
Nanoware Measure and Nanoware Analysis softwares (according to selected model)
User's manual (750 50 0028 03)

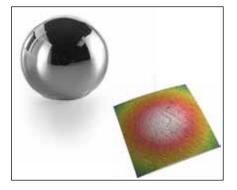
CODE NUMBER

TR Scan Premium	Purpose	Meas. head	Axes	Software
TRSP101DHM 700 405 10 11	3D Measurement of tiny parts	DHM S2	- 1 vertical axis Z	Nanoware STT (2D/3D analysis)
TRSP301DHM	3D measurement of	DHM S2	- 1 vertical axis Z	Nanoware STT
700 405 30 21	metallic parts		- 2 horizontal axes XY	(2D/3D analysis)
TRSP301CCM	Universal 3D	CCM P1	- 1 vertical axis Z	Nanoware STT
700 405 30 31	measurements		2 horizontal axes XY	(2D/3D analysis)

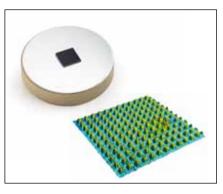
TR Scan Premium can also be specifically equipped according to each application need (head(s) and measuring table, software). An exhaustive list of equipments can be found in the accessories section.

TR SCAN PREMIUM

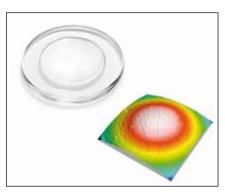
APPLICATIONS



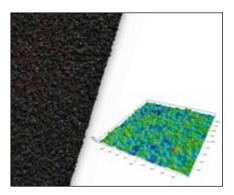
Quality control of a cobalt-chromium polished prosthesis surface (DHM-S2)



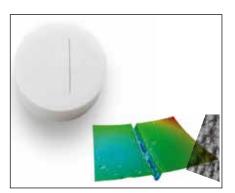
Analysis of a silicon microstructure (DHM S2)



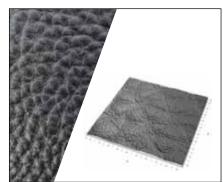
Roughness inspection of micro lenses (DHM S2)



Surface texture analysis of an industrial abrasive material (CCM P1)



Depth measurement of a laser engraving on ceramics (CCM-P1)



Topographic analysis of a leatherette sample (CCM-P1)



Measurment of macroscopic surface textures (CCM P1)